

# MOS FIELD EFFECT TRANSISTOR $\mu$ PA1815

# P-CHANNEL MOS FIELD EFFECT TRANSISTOR **FOR SWITCHING**

#### **DESCRIPTION**

The  $\mu$ PA1815 is a switching device which can be driven directly by a 2.5-V power source.

The  $\mu$ PA1815 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

#### **FEATURES**

- Can be driven by a 2.5-V power source
- · Low on-state resistance

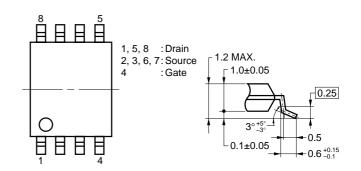
RDS(on)1 = 15 m $\Omega$  MAX. (VGS = -4.5 V, ID = -3.5 A)  $R_{DS(on)2} = 16 \text{ m}\Omega$  MAX. (Vgs = -4.0 V, ID = -3.5 A) RDS(on)3 = 19 m $\Omega$  MAX. (VGS = -3.3 V, ID = -3.5 A)

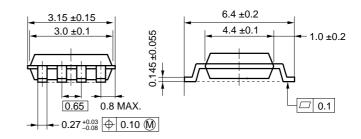
RDS(on)4 = 23 m $\Omega$  MAX. (Vgs = -2.5 V, ID = -3.5 A)

## ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1815GR-9JG	Power TSSOP8

## PACKAGE DRAWING (Unit: mm)

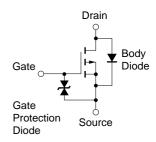




#### ABSOLUTE MAXIMUM RATINGS $(T_A = 25^{\circ}C)$

Drain to Source Voltage	VDSS	-20	V	
Gate to Source Voltage	Vgss	±12	V	
Drain Current (DC)	ID(DC)	±7	Α	
Drain Current (pulse) Note1	ID(pulse)	±26	Α	
Total Power Dissipation Note2	Рт	2.0	W	
Channel Temperature	Tch	150	°C	
Storage Temperature	Tstg	-55 to +150	°C	

#### **EQUIVALENT CIRCUIT**



- **Notes 1.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1 %
  - 2. Mounted on ceramic substrate of 5000 mm<sup>2</sup> x 1.1 mm

#### Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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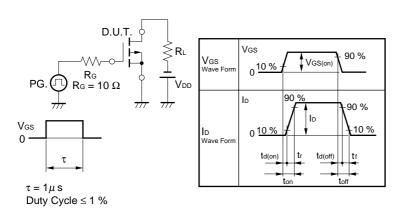
Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.



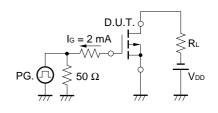
# **★** ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0 V			-10	μΑ
Gate Leakage Current	Igss	Vgs = ±12 V, Vps = 0 V			±10	μΑ
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	$V_{DS} = -10 \text{ V}, \text{ ID} = -1 \text{ mA}$	-0.5	-0.9	-1.5	٧
Forward Transfer Admittance	yfs	$V_{DS} = -10  \text{V},  I_{D} = -3.5  \text{A}$	9	19		S
Drain to Source On-state Resistance	RDS(on)1	$V_{GS} = -4.5 \text{ V}, I_{D} = -3.5 \text{ A}$		12	15	mΩ
	RDS(on)2	Vgs = -4.0 V, ID = -3.5 A		13	16	mΩ
	R <sub>DS(on)3</sub>	Vgs = -3.3 V, ID = -3.5 A		14	19	mΩ
	RDS(on)4	Vgs = -2.5 V, ID = -3.5 A		17	23	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = -10 V		3000		pF
Output Capacitance	Coss	Vgs = 0 V		790		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		410		pF
Turn-on Delay Time	td(on)	VDD = -10 V		45		ns
Rise Time	tr	I <sub>D</sub> = -3.5 A		200		ns
Turn-off Delay Time	td(off)	$V_{GS(on)} = -4.0 \text{ V}$		140		ns
Fall Time	tr	$R_G = 10 \Omega$		160		ns
Total Gate Charge	QG	VDD = -16 V		25		nC
Gate to Source Charge	Qgs	ID = -7 A		5		nC
Gate to Drain Charge	QgD	Vgs = -4.0 V		8.5		nC
Diode Forward Voltage	VF(S-D)	IF = 7 A, VGS = 0 V		0.78		V
Reverse Recovery Time	trr	IF = 7 A, VGS = 0 V		60		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		45		nC

# **TEST CIRCUIT 1 SWITCHING TIME**

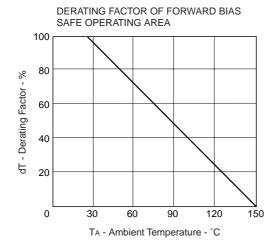


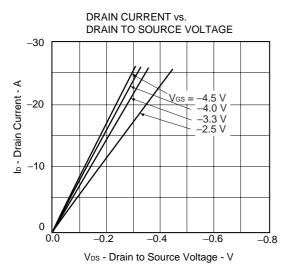
# **TEST CIRCUIT 2 GATE CHARGE**

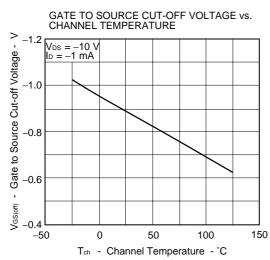


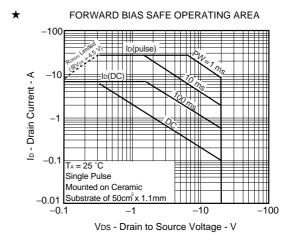


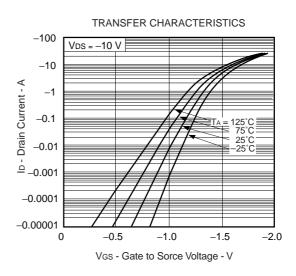
## TYPICAL CHARACTERISTICS (TA = 25 °C)

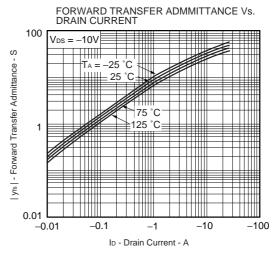






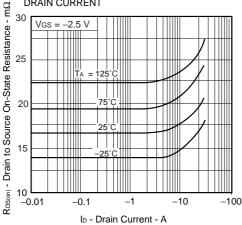




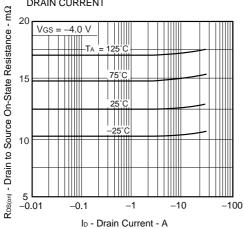


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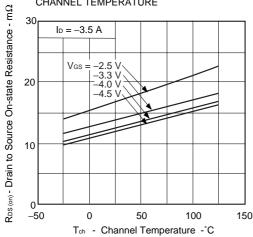




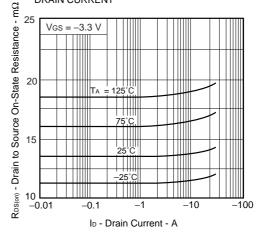
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



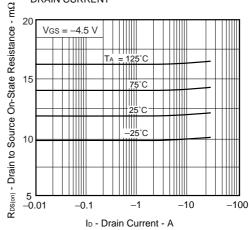
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



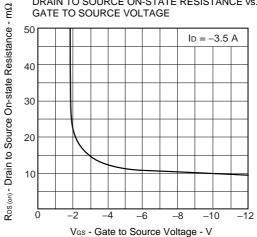
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



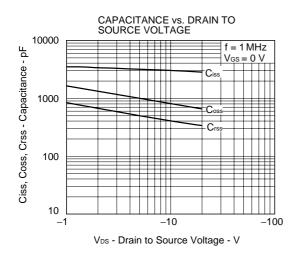
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

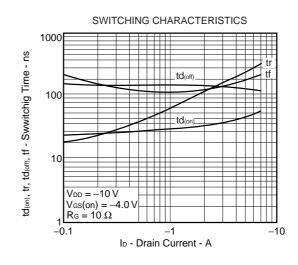


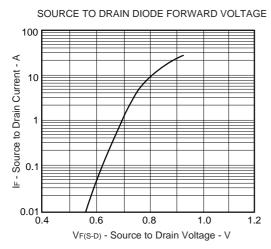
DRAIN TO SOURCE ON-STATE RESISTANCE vs.

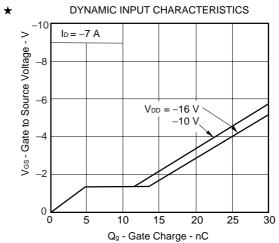




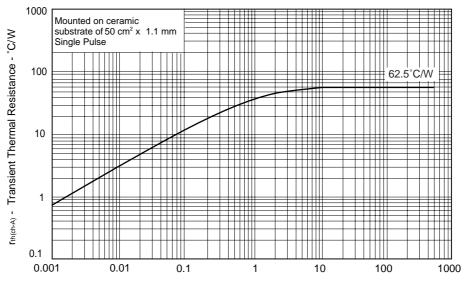








## TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



PW - Pulse Width - s

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